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Autore	Musella, Antonio
Titolo	Nuovi schiavi : il lavoro nell'Italia del Jobs act / Antonio Musella
Pubbl/distr/stampa	Roma : Round Robin editrice, 2015
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Collana	Fuori rotta ; 13
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Titolo	Size Effects in Nanostructures : Basics and Applications / / edited by Victor Kuncser, Lucica Miu
Pubbl/distr/stampa	Berlin, Heidelberg : , : Springer Berlin Heidelberg : , : Imprint : Springer, , 2014
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Descrizione fisica	1 online resource (331 p.)
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Soggetti	Optical materials Electronics - Materials Nanoscience Nanostructures Nanotechnology Physics Building materials Optical and Electronic Materials Nanoscale Science and Technology Nanotechnology and Microengineering Applied and Technical Physics Structural Materials
Lingua di pubblicazione	Inglese
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Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Size effects in semiconductor nanostructures for optoelectronic and photoelectric applications -- Size effects in functional materials for various applications -- Size effects and magnetic behavior.
Sommario/riassunto	The influence of size effects on the properties of nanostructures is

subject of this book. Size and interfacial effects in oxides, semiconductors, magnetic and superconducting nanostructures, from very simple to very complex, are considered. The most general meaning is assumed for size effects, including not only the influence of a reduced dimension/dimensionality, but also specific interfacial effects. Preparation and characterization tools are explained for various nanostructures. The specific applications are discussed with respect to size-related properties. A logic implication of type phenomenon-property-material-application is envisaged throughout this work.